

# FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16717

Generic Copy

Issue Date: 07-Sep-2011

<u>TITLE</u>: Final Notification of Transfer of Low Capacitance TVS (Transient Voltage Suppressor) Array products from ON Semiconductor COM1 Fab in Phoenix (USA) to ON Semiconductor Fab2 in Oudenaarde (Belgium).

PROPOSED FIRST SHIP DATE: 07-Dec-2011

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Fab Site

#### **FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor Sales Office or Jill Daugherty<Jill.Daugherty@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

#### **ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Laura Rivers<<a href="mailto:Laura.Rivers@onsemi.com">Laura.Rivers@onsemi.com</a>>

#### **NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

#### **DESCRIPTION AND PURPOSE:**

This is the final notification announcing that ON Semiconductor is transferring Low Capacitance TVS Array products from ON Semiconductor COM1 Fab in Phoenix (USA) to ON Semiconductor Fab2 in Oudenaarde (Belgium). ON Semiconductor Fab2 is an internal factory that is TS16949 and ISO-14000 certified.

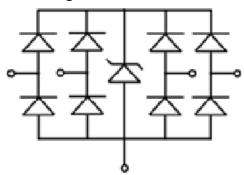
In order to facilitate certain parametric improvements during the transfer, a change was made in the part schematic (shown on the next page). The device pin out remains the same, but this change may be noted during pin to pin ICT testing. The Min VBR parameter will change from 6.0V to 5.5V.

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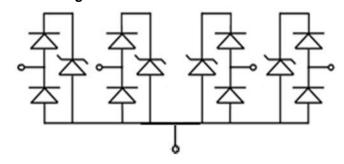


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### **Pre-Change Schematic**



## **Post-Change Schematic**



# **RELIABILITY DATA SUMMARY:**

### **Reliability Test Results:**

Test:	Conditions:	Interval:	Results
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240
HAST+PC	Ta=130C RH=85% ,~18.8psig	96 hrs	0/240
	bias=80% rated V or100V Max		
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/240
RSH	Ta=260C, 10 sec dwell		0/90
DPA	post TC		0/6
DPA	post HAST		0/6

# **ELECTRICAL CHARACTERISTIC SUMMARY:**

**Available Upon Request** 

 $\frac{\text{CHANGED PART IDENTIFICATION}}{\text{Devices with date code marking of }C}:$ 

# **List of affected General Parts:**

ESDR0524PMUTAG ESD7004MUTAG NUP4016P5T5G

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